

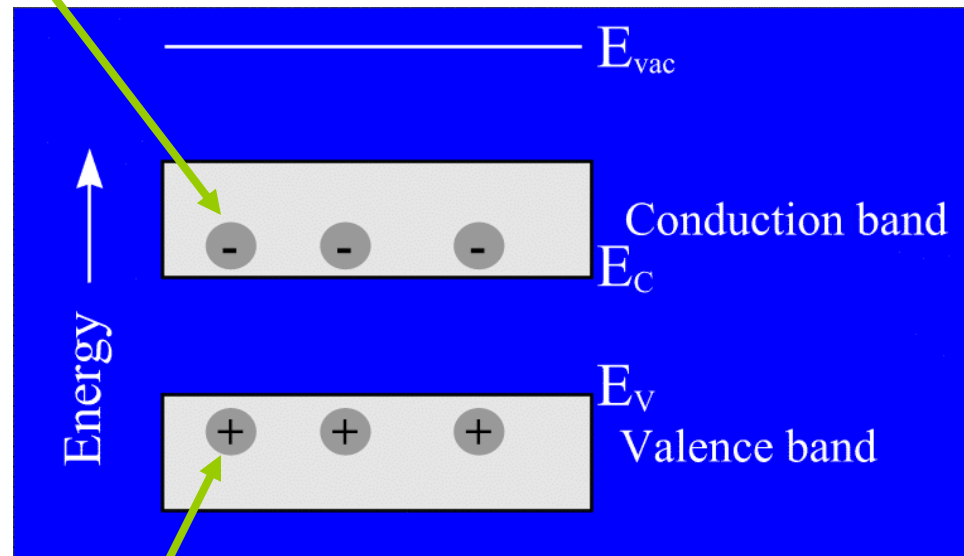
Lecture 3: Electrons in semiconductors II

- Mobile charge carriers
 - Density of states
 - Law of mass action
 - Intrinsic Fermi level
 - Intrinsic carrier concentration
- Doping of semiconductors

Intrinsic and Extrinsic Semiconductors

- In **intrinsic semiconductors** the electron density is equal to the hole density (n_i and p_i).
- An intrinsic semiconductor is one that contains a relatively small amount of impurities compared with thermally generated electrons and holes.
- An **extrinsic semiconductor**, conversely, is a material which contains large amounts of impurities.

Electrons in the conduction band (density, n) carry current

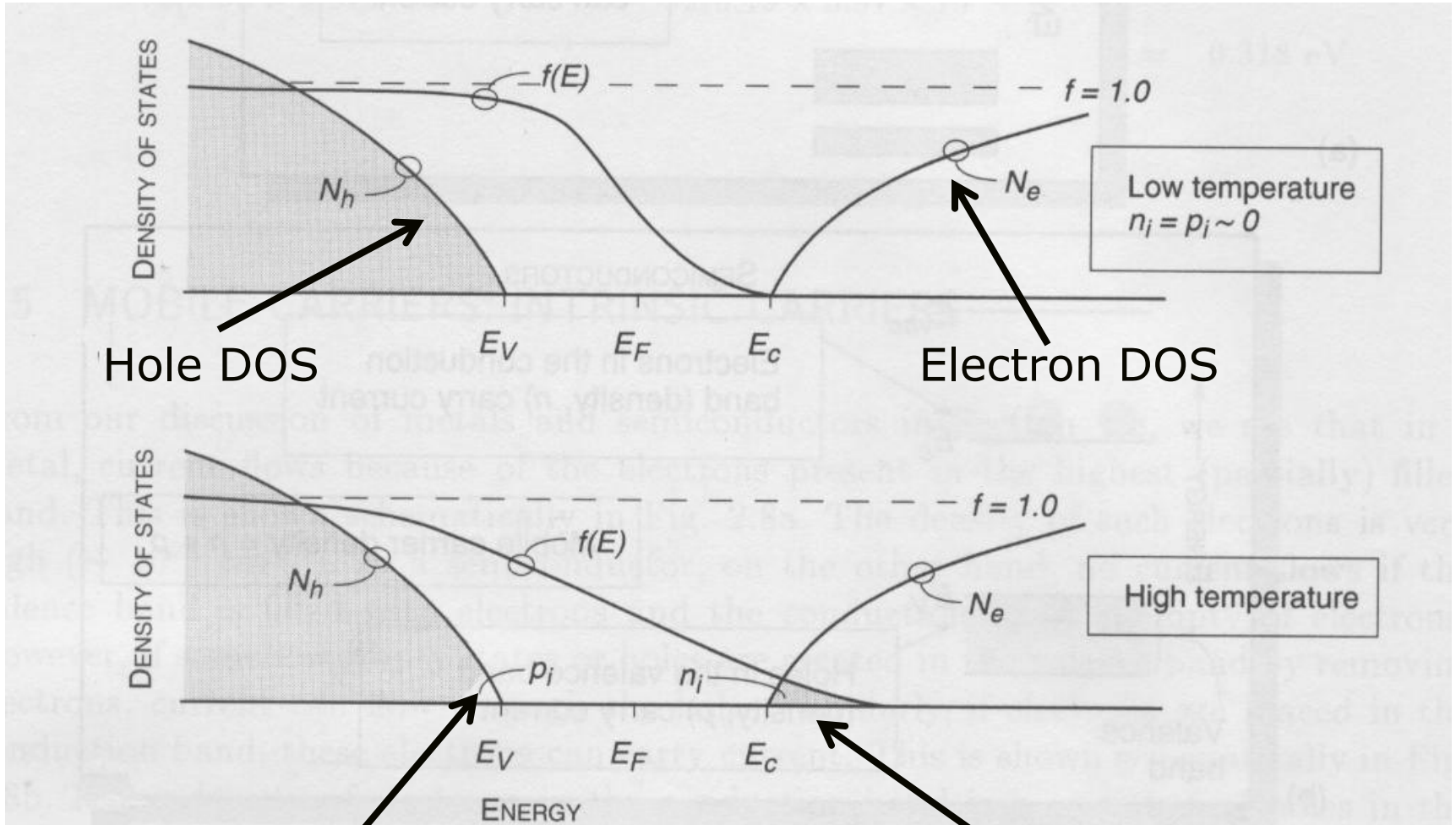


Holes in the valence band (density, p) carry current

- **Mobile carrier density** = $n + p$

Density of states and Fermi function

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Hole DOS

Electron DOS

Hole concentration

Electron concentration

- The intrinsic carrier concentration refers to the electrons (holes) present in the conduction (valence) band of a pure semiconductor.
- It is dependent on the magnitude of the bandgap and the temperature as well as the effective masses.
- The concentration of electrons in the conduction band is:

$$n = \int_{E_C}^{\infty} N_e(E) f(e) dE$$

- $N_e(E)$ is the electron density near the conduction band edge, $f(E)$ is the Fermi function

- The concentration of electrons in the conduction band can hence be written:

$$\begin{aligned}
 n &= \frac{1}{2\pi^2} \left(\frac{2m_e^*}{\hbar^2} \right)^{3/2} \exp\left(\frac{E_F}{k_B T}\right) \int_{E_C}^{\infty} (E - E_C)^{1/2} \exp(-E/k_B T) dE \\
 &= 2 \left(\frac{m_e^* k_B T}{2\pi\hbar^2} \right)^{3/2} \exp[(E_F - E_C)/k_B T] \\
 &= N_C \exp[(E_F - E_C)/k_B T]
 \end{aligned}$$

Effective density of states at the conduction bandedge

$$N_C = 2 \left(\frac{m_e^* k_B T}{2\pi\hbar^2} \right)^{3/2}$$

- The carrier concentration is known when E_F is calculated.
- To find the intrinsic carrier concentration required finding the hole concentration p as well.
- Then hole distribution function is:

$$f_h = 1 - f_e$$

- Then:

$$\begin{aligned} p &= 2 \left(\frac{m_h^* k_B T}{2\pi\hbar^2} \right)^{3/2} \exp[(E_v - E_F)/k_B T] \\ &= N_v \exp[(E_v - E_F)/k_B T] \end{aligned}$$

- **In intrinsic semiconductors the electron concentration is equal to the hole concentration**, an electron in the conduction band leaves a hole in the valence band.

$$np = 4 \left(\frac{k_B T}{2\pi\hbar^2} \right)^3 (m_e^* m_h^*)^{3/2} \exp(-E_g / k_B T)$$

- The product np is independent of the position of the Fermi level and is dependent only on the temperature and intrinsic properties of the semiconductor.
- This is known as the **Law of mass action**
- If n increases, p must decrease. $\rightarrow \mathbf{np = n_i^2}$
- For the intrinsic case $n = n_i = p = p_i$, we take the square root of the above equation:

$$n_i = p_i = 2 \left(\frac{k_B T}{2\pi\hbar^2} \right)^{3/2} (m_e^* m_h^*)^{3/4} \exp(-E_g / 2k_B T)$$

- Setting $n=p$ we can obtain the Fermi level position. The intrinsic Fermi level denoted by E_{fi}

$$\exp(2E_{Fi} / k_B T) = (m_h^* / m_e^*)^{3/2} \exp((E_C + E_V) / k_B T)$$

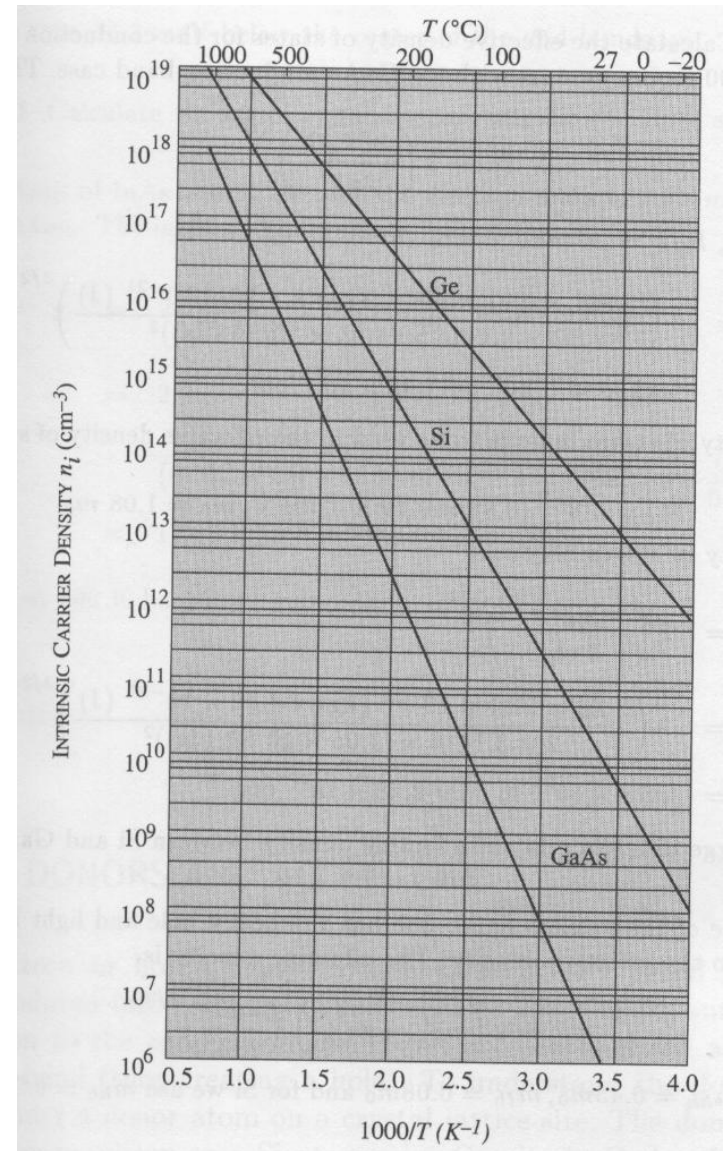
$$E_{Fi} = \frac{E_C + E_V}{2} + \frac{3}{4} k_B T \ln(m_h^* / m_e^*)$$

- The Fermi level of an intrinsic material lies close to the midgap.
- In calculating m_h^* and m_e^* the number of valleys and the sum of heavy and light hole states have to be included.

Material	Conduction band	Valence band	Intrinsic carrier
(300K)	effective density (N_C)	effective density (N_V)	concentration ($n_i=p_i$)
Si	2.78×10^{19}	9.84×10^{18}	1.5×10^{10}
Ge	1.04×10^{19}	6.0×10^{18}	2.33×10^{13}
GaAs	4.45×10^{17}	7.72×10^{17}	1.84×10^6

Carrier concentration: Remarks

- The carrier concentration increases exponentially as the bandgap decreases.
- Notice the strong dependence on temperature.
- In electronic devices where current has to be modulated, the concentration of intrinsic carriers is fixed by the temperature and this therefore detrimental to device performance.



- Once the intrinsic carrier concentration increases to $\sim 10^{15} \text{cm}^{-3}$, the material becomes unsuitable for electronic devices due to the high leakage current arising from the intrinsic carriers.
- High bandgap semiconductors such as diamond (C), and SiC have attracted growing interest.
- They can be used in high temperature applications.
- Pure semiconductors have a low concentration of mobile carriers:
 - Typically $\sim 10^{11} \text{cm}^{-3}$ for intrinsic semiconductors
 - And $\sim 10^{21} \text{cm}^{-3}$ for metals.
- The addition of impurities – **doping** – can be used to change the conductivity of semiconductors.

Example: Intrinsic carriers

- Calculate the position of the intrinsic Fermi level in Si at 300K.
- The density of states effective mass of the combined six valleys of silicon is:

$$m_{\text{dos}}^* = (6)^{2/3} (m_l^* m_t^*)^{1/3} = 1.08m_0$$

- The density of states mass for the valence band is $0.55m_0$. Hence the intrinsic Fermi level is given by:

$$\begin{aligned} E_{\text{Fi}} &= \frac{E_g}{2} + \frac{3}{4} k_B T \ln \left(\frac{m_h^*}{m_e^*} \right) = \frac{E_g}{2} + \frac{3}{4} (0.026) \ln \left(\frac{0.55}{1.08} \right) \\ &= \frac{E_g}{2} - (0.0132\text{eV}) \end{aligned}$$

- The Fermi level is then 13.2meV below the centre of the mid-bandgap.

- There are two kinds of dopants:
 - Donors, which donate an electron to the conduction band. (n-type)
 - Acceptors, which accept an electron from the valence band – and therefore create a hole. (p-type)
- A donor atom should have one or more electrons in its outer shell than the atom it replaces.
- In silicon (a four valent atom) the addition of a pentavalent atom means the remaining fifth electron now sees a positively charged ion to which it is attracted.
- The attractive potential is simply:

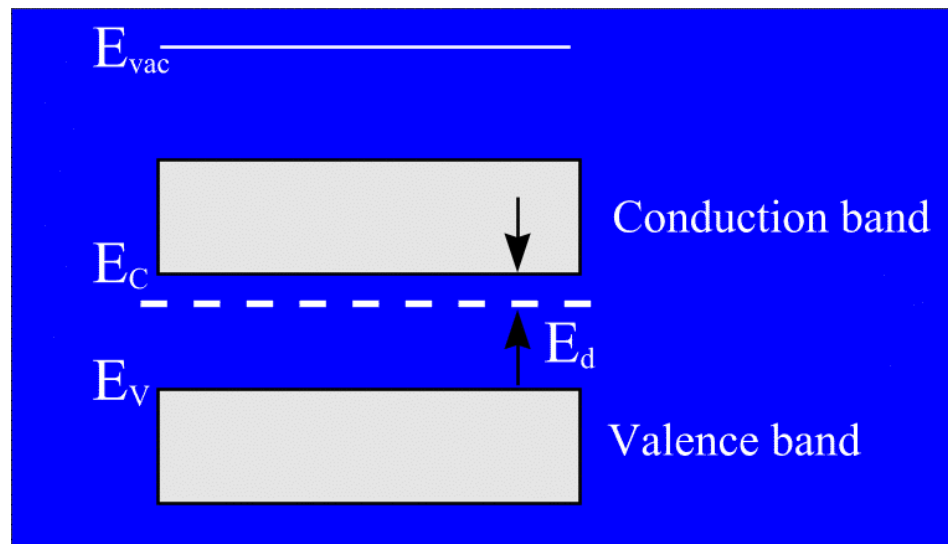
$$U(r) = \frac{-e^2}{4\pi\epsilon r}$$

- The lowest-energy solution for this problem is the **ionisation energy**:

$$E_d = E_C - \frac{e^4 m_e^*}{2(4\pi\epsilon)^2 \hbar^2}$$

$$= E_C - 13.6 \left(\frac{m^*}{m_0} \right) \left(\frac{\epsilon_0}{\epsilon} \right)^2 \text{ eV}$$

- Notice the effective mass m^* is used.
- The energy level is measured from the bandedge.



Limitations of hydrogen formalism

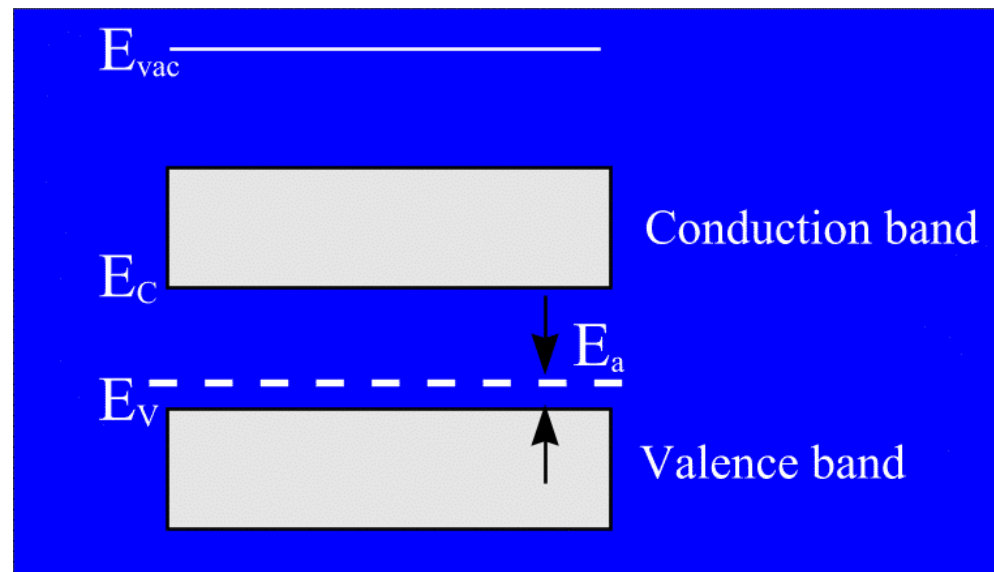
- The simple hydrogen model cannot account for the details of ionisation energy, particularly for the deep impurity levels in semiconductors (ionisation energies $>3kT$).
- Calculated values do predict the correct order of magnitude of the true ionisation energies for shallow impurity levels.
- For shallow impurities in Si and GaAs, there is usually enough thermal energy E_d to ionise all donor impurities, and thus provide an equal number of electrons in the conduction band.
- This condition is called **complete ionisation**.
- Under complete ionisation the electron density (n) equals the donor concentration (N_D).
- Carrier **freezeout** occurs if donor (acceptor) electrons (holes) are tied to their respective lattice sites.

- Another effective mass m_{σ}^* , the conductivity effective mass is introduced to describe how electrons respond to external potentials.
- This mass is used for donor energies as well as for charge transport in an electric field.
- For direct bandgap semiconductors, this is the effective mass.
- For indirect materials such as silicon the conductivity mass is:

$$m_{\sigma}^* = 3 \left(\frac{2}{m_t^*} + \frac{1}{m_l^*} \right)^{-1}$$

- Reminder: The density of states mass represents the properties of the electrons at a constant-energy surface in the band structure.

- The acceptor levels are produced when impurities that have a similar core potential as the atoms in the host lattice, but have one less electron in the outer shell, are introduced.
- Group III elements can act as acceptors in Si or Ge.
- Under complete ionisation the hole density (p) equals the acceptor concentration (N_A).



Summary of donors and acceptors

Semiconductor	Impurity (Donor)	Donor Energy (meV)	Impurity (Acceptor)	Acceptor Energy (meV)
GaAs	Si	5.8	C	26
	Ge	6	Be	28
	S	6	Mg	28
	Sn	6	Si	35
Si	Li	33	Be	45
	Sb	39	Al	67
	P	45	Ga	72
	As	54	In	160
Ge	Li	9.3	B	10
	Sb	9.6	Al	10
	P	12	Ga	11
	As	13	In	11

Doped semiconductors are referred to as **extrinsic** semiconductors.

- We can now write the Fermi level in terms of the effective density of states N_C and the donor concentration N_d :

- Recall: $n = N_C \exp\left[\frac{(E_F - E_C)}{k_B T}\right]$ and $n = N_d$

- Therefore: $E_F - E_C = k_B T \ln\left[\frac{N_d}{N_C}\right]$

- Similarly for shallow acceptors $p = N_A$ and:

$$E_V - E_F = k_B T \ln\left[\frac{N_a}{N_v}\right]$$

- For higher donor concentration, the smaller the energy difference $(E_F - E_C)$, the Fermi level moves closer to the bottom of the conduction band.

- Considering material that have a dominance of donors (n-type) or acceptors (p-type).
- There is no longer equality between the electrons and holes: $n - p \neq 0$
- The law of mass action still holds – and only changes at high doping levels:

$$np = \text{constant} = n_i^2$$

- As indicated, when the semiconductor is doped n-type (p-type), the Fermi level moves towards the conduction (valence) bandedge.
- When the Fermi level approaches the bandedge, the Boltzmann approximation is not very good and the simple expressions relating the carrier concentration and Fermi level are not very accurate.

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